



520.43279X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: S. YAMASHITA et al
Application No.: 10/706,972
Filed: November 14, 2003
For: QUALITY MONITORING SYSTEM FOR BUILDING
STRUCTURE, QUALITY MONITORING METHOD FOR
BUILDING STRUCTURE AND SEMICONDUCTOR
INTEGRATED CIRCUIT DEVICE
Art Unit: 2863
Examiner: H. VO

AMENDMENT

MS: AMENDMENTS

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

May 2, 2005

Sir:

In response to the Office Action dated December 1, 2004, the period of response for which extension is requested by the attached Petition for Extension of Time, please amend the above-identified application as listed below and as set forth on the following pages:

Amendments to the Claims;

Amendments to the Abstract; and

Remarks are included following the amendments.